

Electron Beam Deposition of Circuits

Hand-drawn schematic diagram of a mechanical system, likely a manipulator or material handling device. The diagram includes various components labeled with numbers and text. Key components include:

- MATERIAL B Feed Servo** (33)
- MATERIAL A Feed Servo** (31)
- Repeat Cycle Programming Recorder or Computer** (11)
- Sealing Door** (2)
- base** (40)
- table** (41)
- Manipulation Servo** (47)
- Door Servo** (49)
- X Direction Servo** (44)
- Y Direction Servo** (45)
- CRAMP SERVO** (43)
- vac. chamber** (14)
- manipulator** (12)

A note at the bottom states: "manipulator moves through door when opened to place part on board onto table 41 and/or remove at therefrom".

A handwritten note at the top right says: "Bedin may also X-y deflection is".

A handwritten note at the bottom right says: "I should".

The diagram is labeled **FIG. 1**.

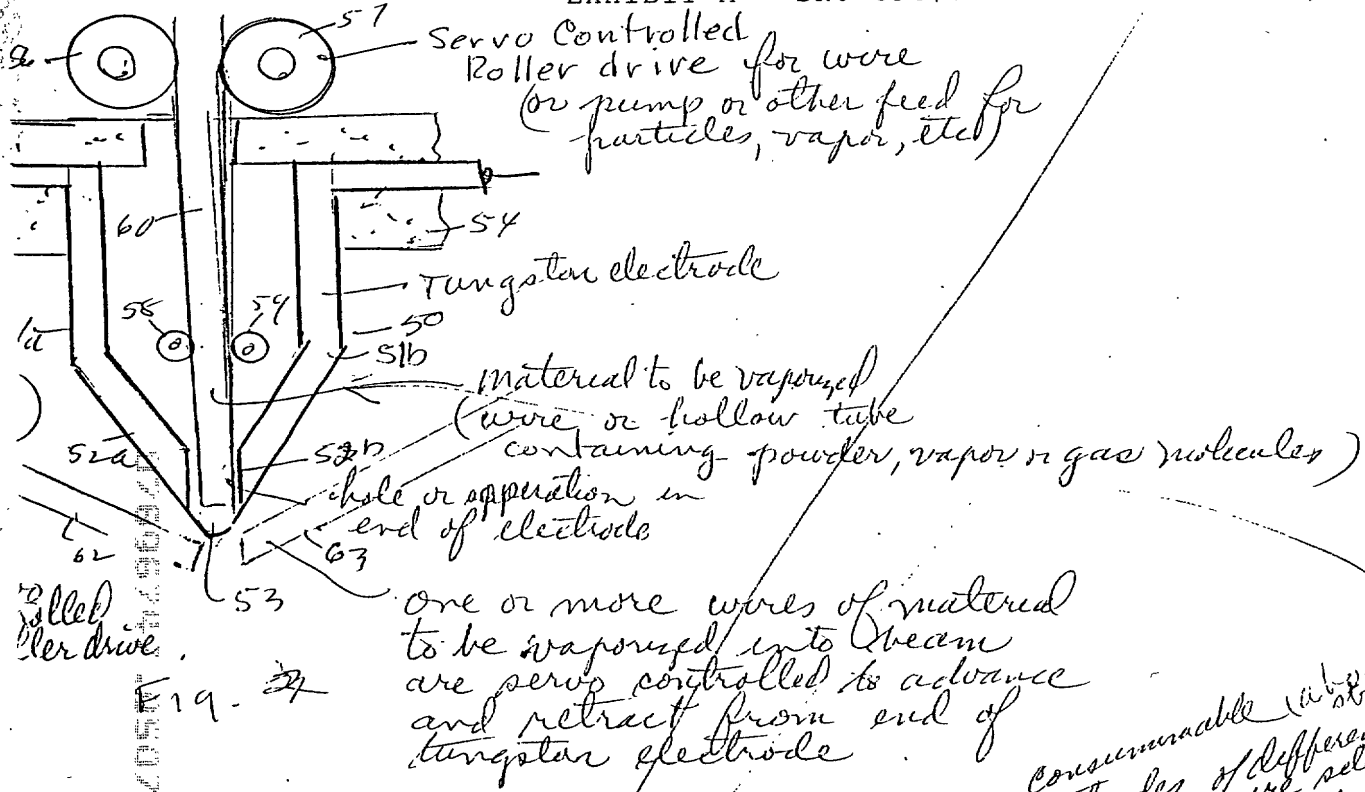
Fig. 1

J. Smelt.

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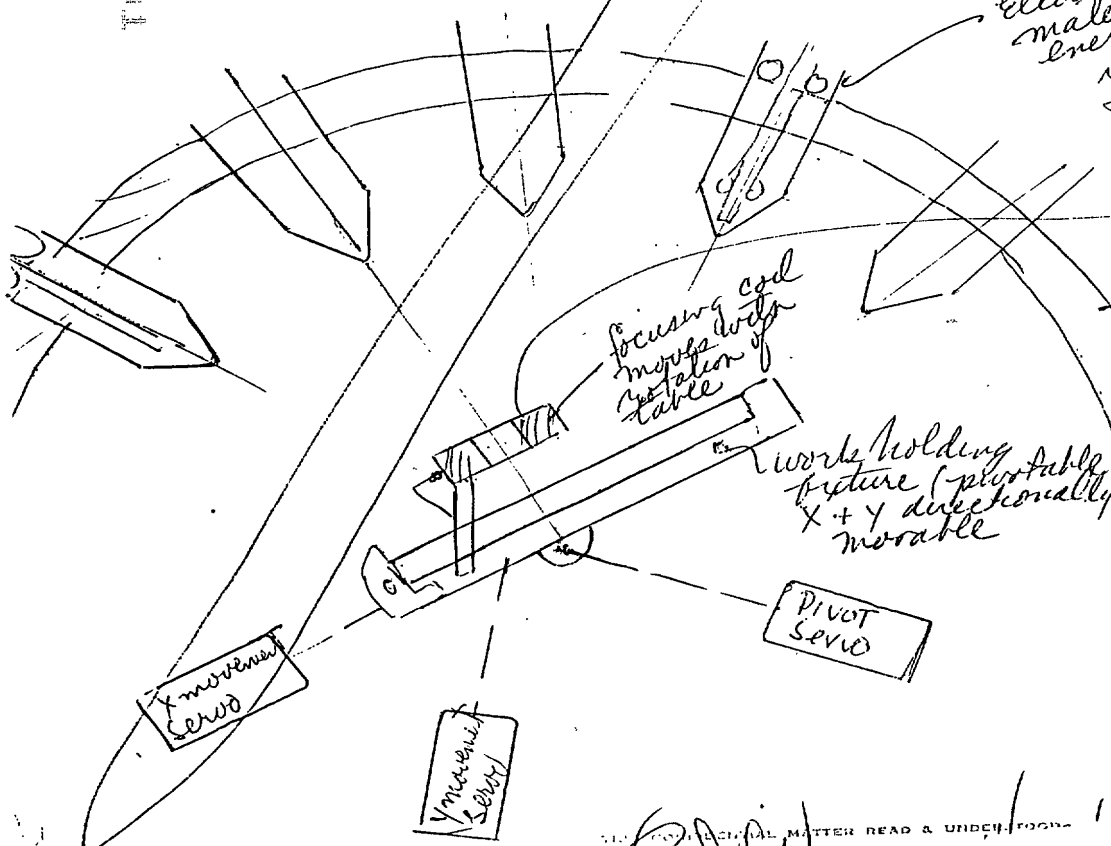
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consumable (above) structure
electrodes of different materials are selectively energized through a rotary switch connected to necessary source of potential

also rotate and linearly control focusing vacuum chamber



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In the electron beam apparatus of pp 140 & 141 the claims for which I have been working on over the past 10 months it is noted that:

(1) The beam may be deflection controlled by means of an analog signal or signals using deflection plates of conventional design

(2) The beam focus

All servos such as drop ~~to~~ vac. chamber opening & closing servo, work positioning servo, ~~and~~ servos for feeding materials into the beam manipulator for admitting and removing workpiece from chamber, pivot clamping servo, etc. as well as the means for controlling focus, deflection, and selection of (one of a multiple of) beam may be automatically controlled in an automatic cycle of operation by means of a programming means such as a magnetic or other recorder on which is recorded the necessary analog and/or digital signals to effect such control in which record is operated and transduced from to derive vac. signals in a predetermined sequence -

(3) Material to be deposited may be admitted to beam as a rod or wire, powder, liquid, or gas which materials are carried along in beam to work piece and focused thereon by beam energy or modulation may be controlled by a reproduced analog or digital signals to prepare (heat or erode, melt or vaporize) surface base or surface on which selected deposits are to be made

(4) Chemical reactions, alloying, doping, etc may take place in beam or by means of beam and material therein deposited on or diffused into surface intersected by beam.

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machining or otherwise chemically changing. Material deposited may be effected by change of beam energy, etc. or by means of more auxiliary beams generated by same gun or chamber (different guns) are similarly deflection controlled and

material to be deposited (wire, powder, vapor, gas) may be positionally controlled by servo controlled by the programming controlling the other variable to be focused or moved into the volume focus of the beam directly above surface

may be focused in gun into which material is selectively fed and controlled by programming means. After focus beam may be diverged or directed as a narrow beam against surface of work and/or deflectionally

auxiliary beams may feed into main beam after or at its focus or near its generation which auxiliary beams contain atoms of material to be deposited onto surface by beam which may be deflection controlled in accordance with a programmed

optical maser may be used as an x-ray beam generator in conjunction with arrangements or in place of electron generating means thereof. Matter beam may be travelled inside or parallel to electron beam or may be directed at the focus of electron beam to cooperate in machining, otherwise affecting surface of work or evaporating material to be fed to beam.

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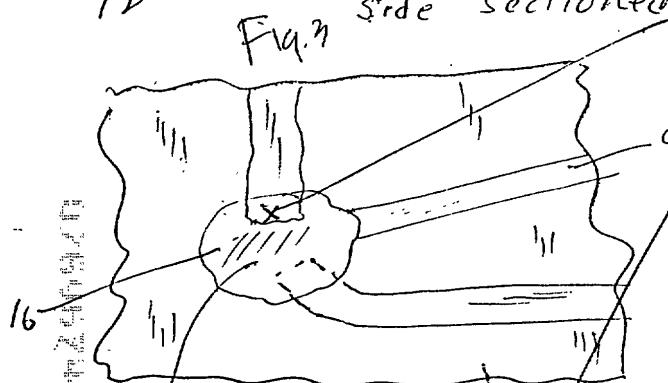
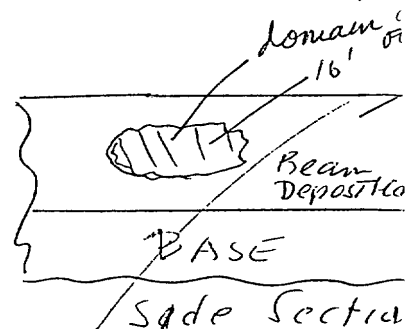
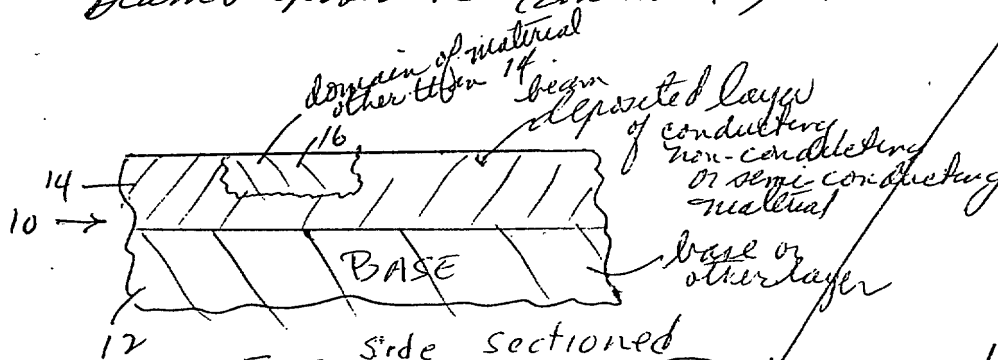
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Beam Deposition (Continued)



domain or surface deposits of semi-conductor device (material admission to beam or electrode controlled by computer or programming means)

beam may be concentrated here to diffuse deposited metal into domain deposits, conducting layer beam deposited along predetermined path on base

all deposits are by beam controlled by analog signals reproduced from a recorder, which recorder programmes signals (reproduction) also control material selection (into beam, rate of flow thereof, travel of beam across work, and on-off of beam, position, handling of work within and in and out of vacuum chamber, etc.)

Feedback signals for indicating how much material is deposited and where to control beam position, flow and selection of different materials to be admitted to beam may be effected by means of a reading electron beam directed by computer or programmed (recorded signals) to scan selected area or scanning entire target as the material is deposited or during periods when material

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* being deposited (inspection scanning period). The raw video signal derived by beam scanning may be analyzed by techniques as described in pending application "Automatic Inspection System" digitally determining in digital form the characteristics (optical characteristics) of the material inspected.

Spectroscopy may also be employed in which a beam is directed against the deposited material and causes an emission of electrons therefrom which are spectrally analyzed, the results of which are used to control further deposition removal of deposited material.

Material from p. 138 to this point read by Andre Math on

Ernest Waldmeyer III

Classification of Electron Beam Deposition Apparatus & Methods

The following are arrangements, apparatus and methods conceived relating to electron beam manufacture of micro-circuit circuits which I intend to incorporate in a number of applications.

Deflection and intensity control of deposition (or machining, welding, electron beam or beams) attained by one of the following techniques:

- reproduced magnetically recorded video picture signal or signals.
- video signal generated by scanning optical recording
- output of digital recorder
- output of comparator (summing amplifier) fed (a) or (b) above plus feedback signal generated by scanning either or both beam containing deposition material or surface containing deposited material.

Correction for over or incorrect area deposition may be made controlling beam per-se (by computer command signals or input of summing amplifier being fed command reproduced video signal and feedback scanning signal) which beam either

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machines or vaporizes material already deposited. **
 ** Vaporized material (vaporized by corrective beam) may be
 removed from surface of workpiece by another beam of
 deflection controlled or otherwise positioned to effect said
 removal.

Correction for over deposition may also be made - deflection controlled beam containing an oxidizing or other compound. For chemically changing part of deposited material to an

work may be positionally controlled by command and receiving command and feedback signals as described or command and feedback signals as described.

Deflection control of beam (x, y position plus intensity modulation) plus position of focus (z control) depending on position of the surface being scanned.

- (a) depositing semi-conductors, metal or dielectric materials
- (b) depositing plural materials simultaneously different
- (c) " " " at different times by different single beam.
- (d) introducing different materials at same or different times
- (e) welding, machining, vaporizing deposited material.

III Feedback signal compared with reference command (represented by beam control signal) is generated by:

- (a) Beam scanning and analysis of ionized or vaporized particles therein as beam is generated and material(s) admitted there
- (b) optical beam or work scan plus analysis
- (c) Spectroscopy or spectrographic (automatic) analysis - mass spectrograph + scan
- (d) electron beam scan of deposited work with a video read beam

TV Material Feed (to beam) by and as:-

- (a) Rod or wire, servo driven into beam, into ^{intermediary} beam focus, electrode generating beam (units ~~or~~ between electrodes) or directly into output receiving reproduced command signal plus feedback signal.
- (b) servo controlled powder feed (as above)
- (c) servo valve controlled (as above) feed of liquid control

ation material into beam (or vaporized deposition material into beam),

Plural Beams

Plural reproduced deflection control signals plus trial control or reference signals, plus work positioning signals (optional), plus focus adjustment signals (optional) as mentioned above are used to simultaneously control beams each depositing different material alternately.

Beam Deposition Techniques (Miscellaneous features)

(a) Electron beam plus photographic techniques.

(1) Beam deposits components onto conducting film pattern formed by photo-etching, photocomposition (exposure to light and developing).

(2) Optical beam (laser light beam) is deflection controlled and cooperates with deflection controlled electron beam in welding, machining, effecting deposition, chemically reacting on deposited materials, deposited by electron beam, etc. Laser light beam may also be used to carve photosensitive film, expose it, per se, develop image, used for contact purposes (vaporize or machine material (film) deposited by electron beam, vaporize material(s) to be deposited or directed by electron beam, etc. work, etc. Laser beam deflection controlled by servo controlled mirrors controlled by reproduced command signal or output of comparator or computer.

(b) Plural beams cooperate. One vaporizes (laser or electron beam) material to be deposited, feeds it at or to second deposition beam, which is deflection controlled and deposits material, and beam scans either second beam or surface which has just received material to provide a feedback signal to a comparator (summing amplifier or other) which provides an output to control both first and second beams (i.e. on-off or intensity or focus of first beam and position of second beam) (first and second beams are controlled by respective command signals fed to

well by passing beam thru mask

respective comparator means each of which receives same feedback signal generated by third beam scanning what is being or was just deposited

(c) An apparatus for repairing, modifying or adding micro-miniature circuits has also been conceived based on beam scanning the circuit already deposited (surface scanning) and determining by reading with the beam the physical-optical or atomic structure of the circuit, by x-ray scanning, by optical scanning, said circuit (with a modulated light beam) or by a combination of two or three of these scanning techniques, has been conceived. The output signal derived by scanning is fed to a computer, which thereafter provides signals for controlling beam deflection, modulation, position of workpiece, material selection and feed to beam, mask selection, etc. to effect a desired repair, change in structure, etc.

(d) Vaporization of material in a primary electron beam or by means of a molten through which beam of the deposited beam is passed and picks up the material to be deposited, carrier.

(e) Material changed by, new composition(s) formed in a beam directed against a workpiece by either the action of the beam per se or the reaction of the beam (temperature, etc.) and two or more of the materials admitted thereto or one or more admitted material and material of the workpiece.

(f) Growth of predetermined crystal structure by means of melting material(s) admitted thereto and deposited, or by a combination of materials admitted to beam being deposited thereby onto a crystal being grown. Programmed control of beam deflection, on-off, modulation, focus; crystal movement; material flow into beam (based on feedback derived by scanning beam, crystal, etc. (as described above) fed into comparator; also a command signal and providing difference signal for correction.

(g) Creation of mask through which erosion electron beam is directed for chemically or mechanically affecting (or changing chemically, welding, etc.) the workpiece by means of photosensitive mask material, thermoplastic recording film, of General Electric Co. which mask is formed by exposure to a writing beam of said mask material which writing beam is modulated to affect the desired image (transparent and opaque or reverse pattern in the mask. Mask may be in the field of the

sted against the workpiece (in path of beam)

(b) Use of a unique mask in beam path made of a grating - as a diffraction grating produced by beam etching thin plate selective and controlled deposition of material introduced ribbon or to or after passing thru mask. Plural diffraction gratings used at right angle to each other will produce line beams less than .001 inches in diameter.

(c) Use of a mask to break up beam intense electron or maser beam into a plurality of beams directed thereafter against selected areas of the workpiece for effecting welding, machining (hole drilling), erosion or deposition onto said selected areas.

(d) Program control (plus feedback where necessary) of beam turn (deflection), focus, etc. & position of workpiece, and different materials fed into beam to selectively deposit different materials onto different areas of workpiece.

(e) Exposure, machining, chemically changing, development and use of a photosensitive material to form a circuit by means of beam and use of beam to deposit semi-conducting, dielectric or insulating materials onto selected areas of photosensitively developed circuit all by automatic control as above.

J. Stuller

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Extrude multiple sheets or strips apart, & filaments
of different materials) + laminate continuously.

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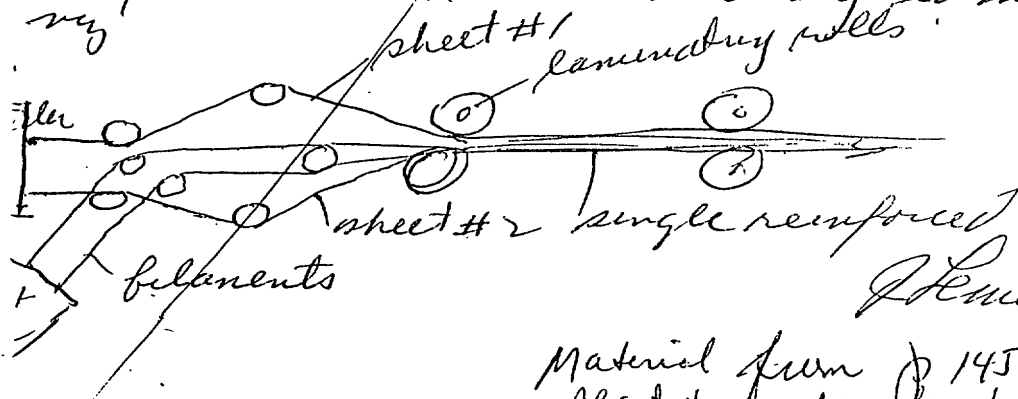
to rods, tubes, wires or other structural members made of
plastic filaments or metal whiskers (single crystals
of metal of exceptional strength) which are compacted
together and bonded or welded where they cross.
They may be encapsulated in another plastic, metal,
sandwich powdered metal, etc to form solid, filament
reinforced structures.

It is conceived to simultaneously extrude a plurality
of sheets of thermoplastic or ribbons thereof from a single
die but from spaced-apart slit openings and guide
said sheets or strips as follows:

(a) First guide apart, ^{continuously} admit filaments (reinforcing
or decorative), or cloth, threads or other material as a
continuous or broken web between two of said strips and
continuously laminate into a single, integral sheet
of reinforced material.

(b) Drive each sheet thru polishing rolls and
then laminate (improved clarity).

(c) Simultaneously extrude from another extrusion
hammer, a plurality of reinforcing filaments (of glass,
polypropylene, or other plastic), guide these between
at least two of the strips, or ribbons or sheets
not extruded and continuously laminate together
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Enclosed.

Material from p 145 to this point
read & understood by me this 4th
day of September